Notice of References Cited	Application/Control No. 10/567,326	Applicant(s)/Patent Under Reexamination SEKINO ET AL.		
	Examiner	Art Unit	Page 1 of 1	
	Edu E. Enin-Okut	1795		
II S PATENT DOCUMENTS				

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0209133	10-2004	Hirsch et al.	429/022
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Ρ					
	Ø					
	R					
	S					
	Τ					

## **NON-PATENT DOCUMENTS**

	NON-I ATENT DOCUMENTO			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	V			
	w			
	х			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.